

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/725,970 | Applicant(s)/Patent Under Reexamination BRANDSTATTER ET AL. | |
| | Examiner Hae M Hyeon | Art Unit 2839 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-4,405,194 | 09-1983 | van Lierop, Dirk F. W. | 439/622 |
| | B | US-4,790,776 | 12-1988 | Iijima, Makoto | 439/695 |
| | C | US-5,282,753 | 02-1994 | Su, Tun-Li | 439/106 |
| | D | US-5,662,484 | 09-1997 | Blanche, Stephen A. | 439/106 |
| | E | US-6,168,443 | 01-2001 | Mullen et al. | 439/106 |
| | F | US-6,190,212 | 02-2001 | Brown et al. | 439/736 |
| | G | US-6,454,612 | 09-2002 | Wang, Ming-Shan | 439/694 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.